

**Notice of References Cited**

Application/Control No. **10/026,189** **10/026,326** Applicant(s)/Patent Under Reexamination **EMERY ET AL.** **MeTs et al.**

Examiner **Kuan S. Lu** **Anh Ly** Art Unit **2467** **2162** Page 1 of 1

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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